



September 22, 2014

**RELIABILITY DATA
CMOS EPROM NVM**

SUMMARY:

Silego performs a quarterly data retention test on the PAK™ family of products as part of the on-going reliability monitor. This family of products is fabricated at TSMC and incorporates the e-memory NVM feature. Data retention is performed in accordance with JESD22-A103 condition B, 1000 hours at +150°C. To date 1,815,000 device-hours have been accumulated with no failures.

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